



# Comparison of alternative approaches to high-power thin-film LED chip design

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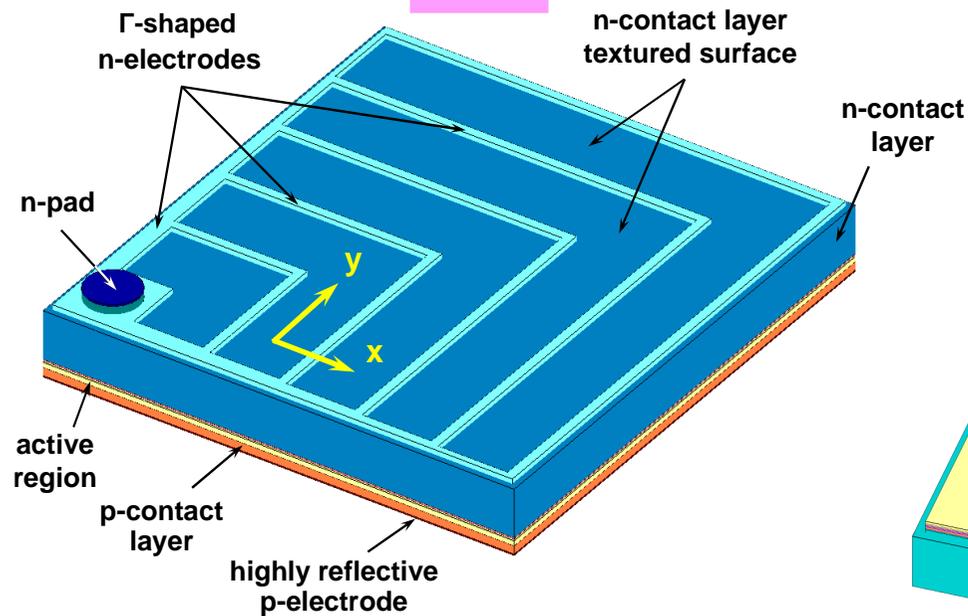
STR Group – Soft-Impact, Ltd.

# Vertical and planar LED dice with removed substrates



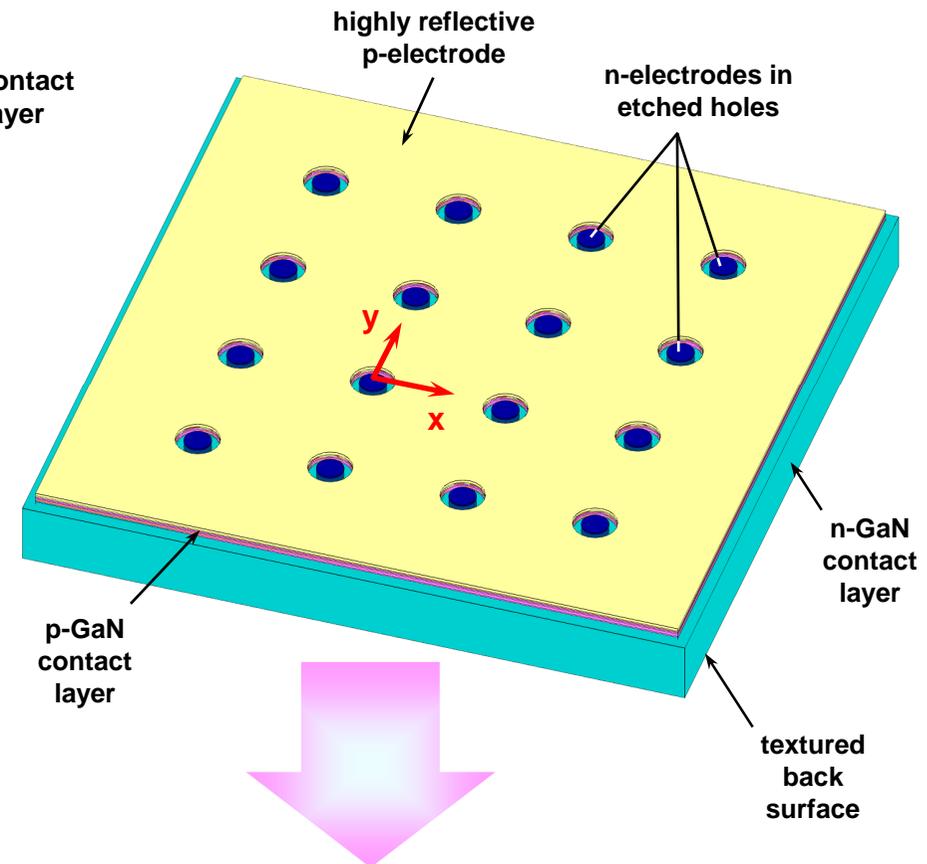
O. Shchekin et al., Appl. Phys. Lett.  
89 (2006) 071109

## 1000×1000 planar LED die



## 815×875 vertical LED die

V. Härle et al., Proc. SPIE 4996 (2003) 133;  
phys. stat. solidi (a) 201 (2004) 2736

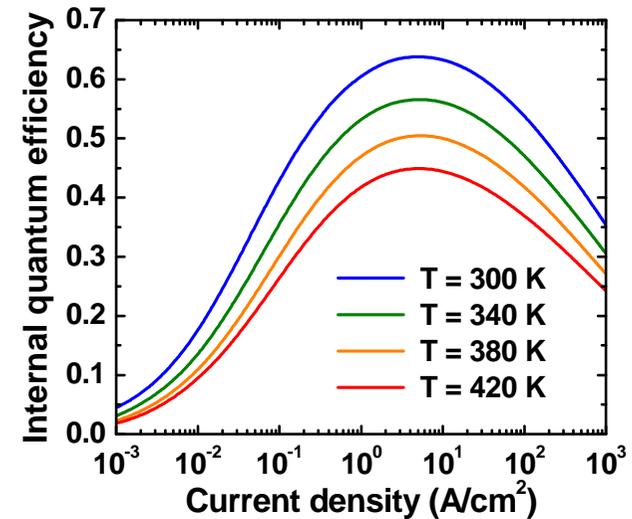




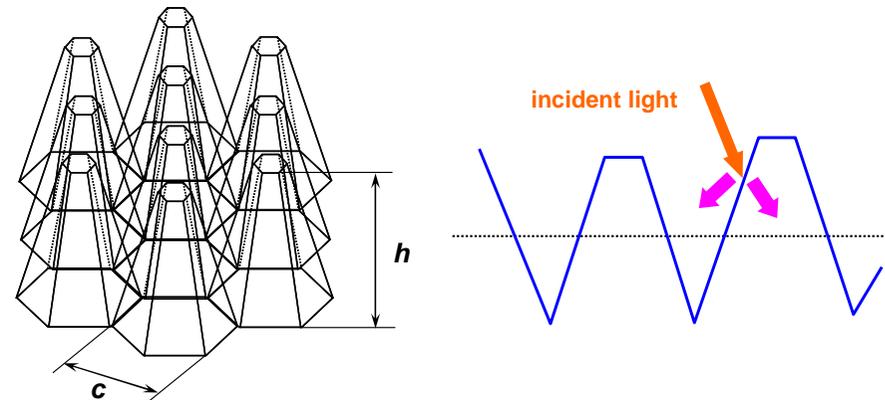
## Key elements of simulation model

SimuLED™ package is used for modeling:  
<http://www.str-soft.com/products/SimuLED>

- 3D coupled simulation of electrical, thermal, and optical processes in the LED die
- Auger recombination is considered is the main non-thermal mechanism of the IQE droop at high current densities
- textured surface is modeled by closely packed hexagonal pyramids with the aspect ratio  $h/c \sim 4$
- optical properties of Au and Ag are used for n- and high-reflective p-electrodes, respectively



no electron leakage is predicted for InGaN MQW LED structure

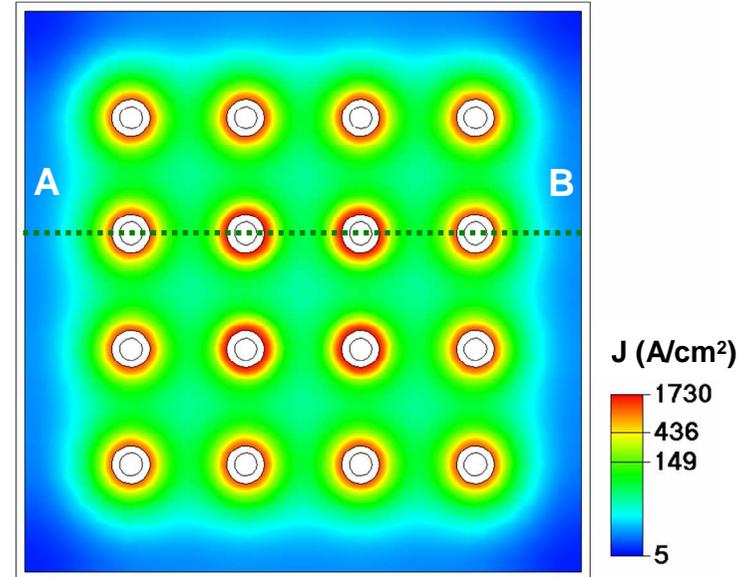
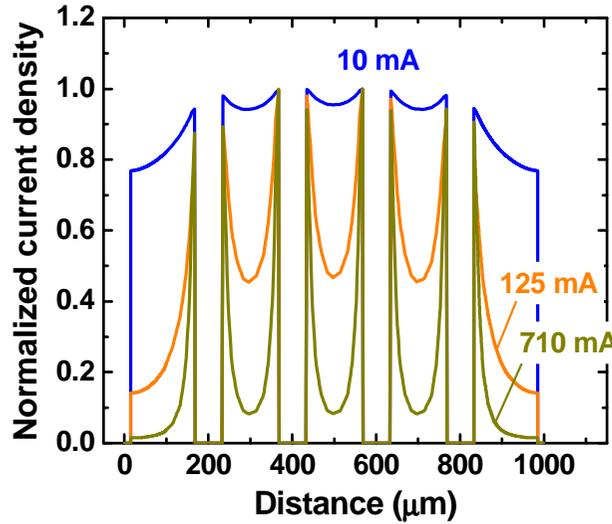


# Current crowding in the active region

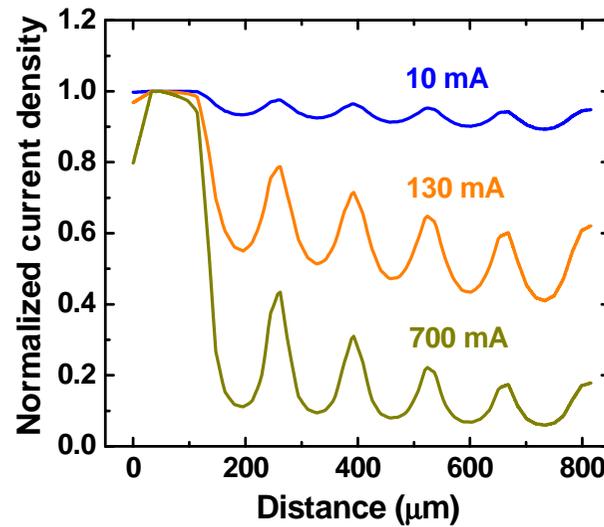
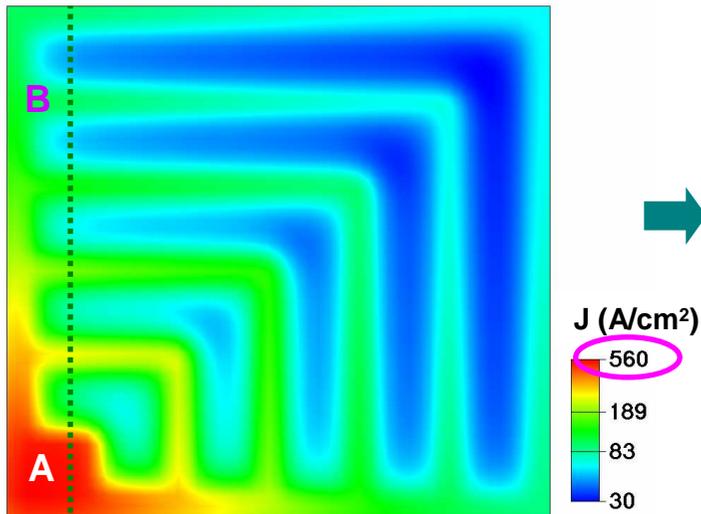


The mean current density in both dice is  $\sim 96 \text{ A/cm}^2$

$I = 960 \text{ mA}$

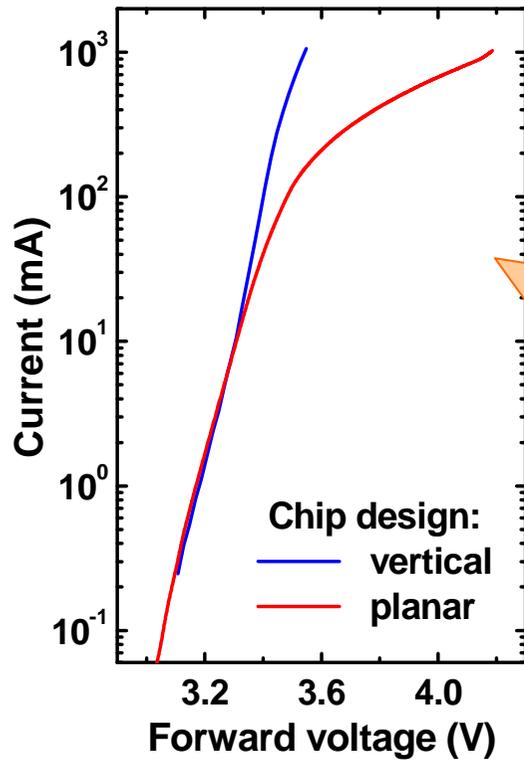


$I = 700 \text{ mA}$



current density non-uniformity depends on the total operating current

# Current crowding effect on local overheating and I-V curves



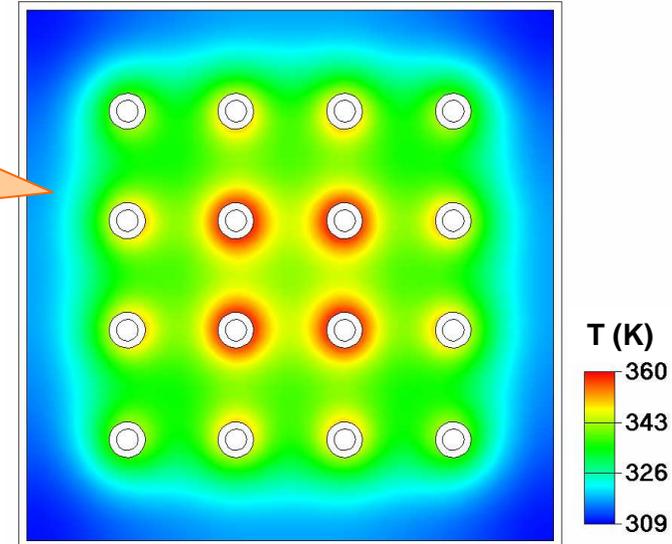
a greater local active region overheating in the planar die

a higher series resistance of the planar LED caused by a smaller total n-electrode perimeter

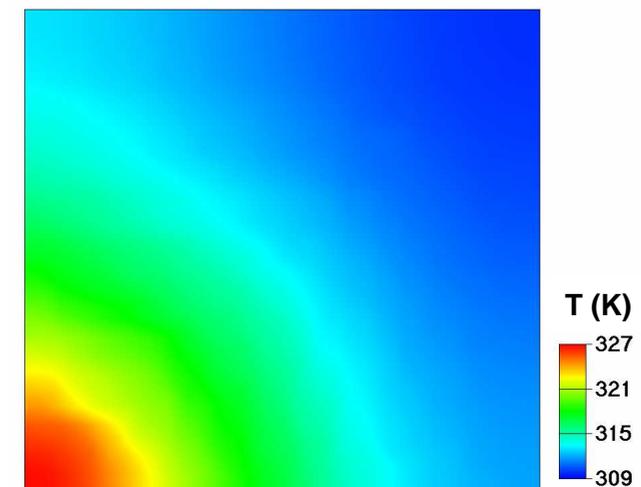
$$R_s \approx (L_{sp} / \sigma_n d_n p)^{-1}$$

electron concentration in the n-contact layer is  $\sim 1 \times 10^{18} \text{ cm}^{-3}$  in both dice

$R_{\text{therm}}$   
9.5 K/W



$R_{\text{therm}}$   
8.2 K/W

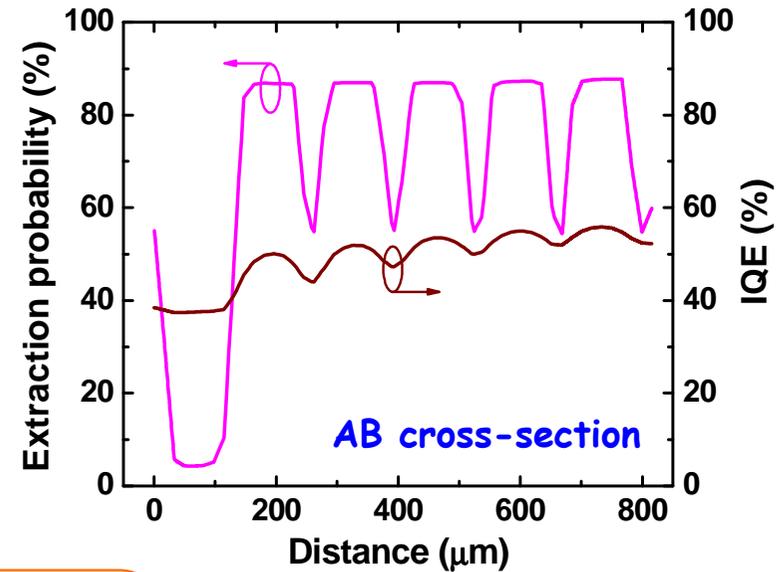
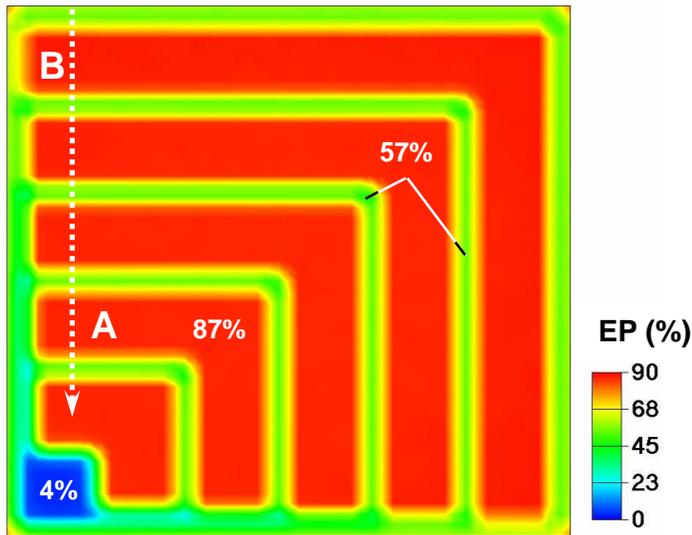


# Light extraction from the vertical LED die

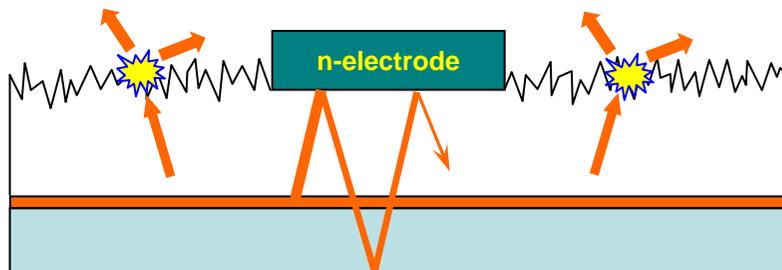


immersion media:  $n_r = 1.3$

$I = 700 \text{ mA}$



probability of light extraction falls down under and next to n-electrode



distribution of extraction probability is nearly independent of current

light generated under n-pad is not practically extracted from the die because of incomplete multiple reflection from metallic electrode

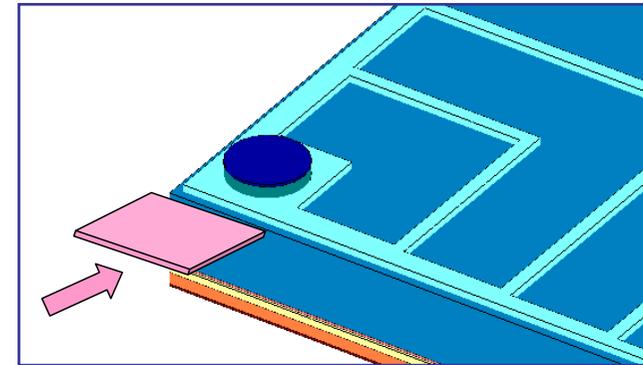
# Dependence of light extraction efficiency on current for vertical die



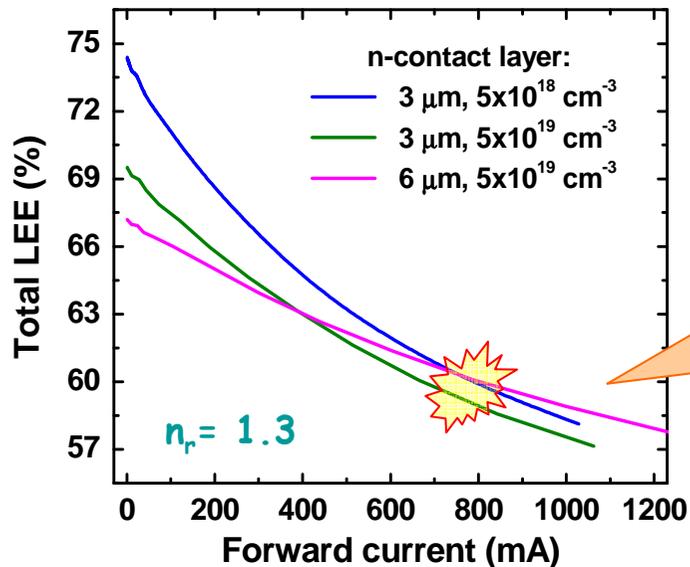
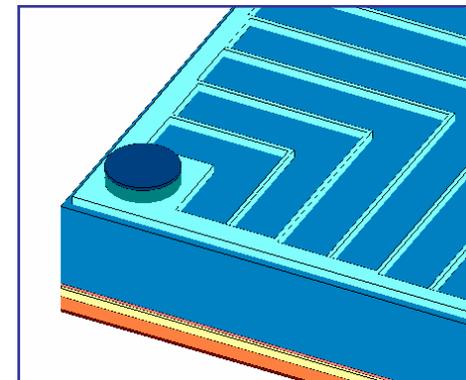
variation of n-contact layer parameters affects weakly the current crowding and, hence, the LEE at ~700-800 mA

alternative approaches are required

Approach 1: insertion of an insulating layer under the n-pad to avoid parasitic current flow in this region



Approach 2: use of narrower  $\Gamma$ -shaped electrodes with reduced spacing

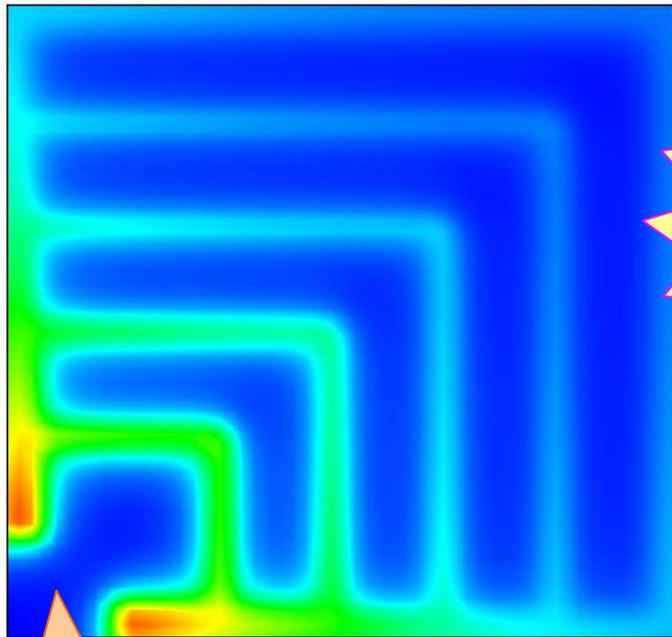


strong dependence of LEE on forward current

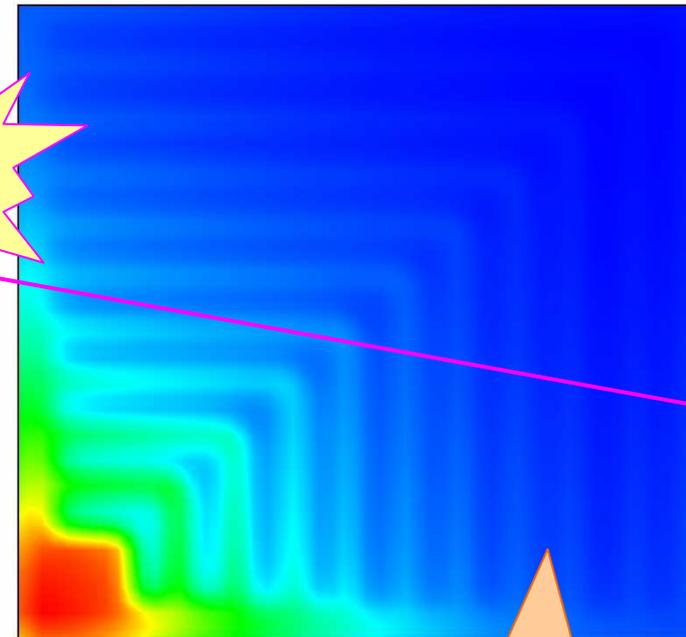
# Current spreading in vertical LED dice of modified designs



Total current through the diode  $I = 700 \text{ mA}$



it was  
~560  
A/cm<sup>2</sup>



parasitic current flow under the n-pad is partly suppressed

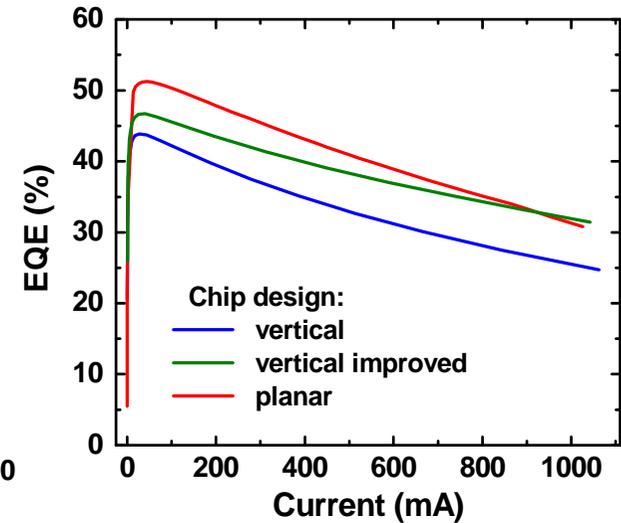
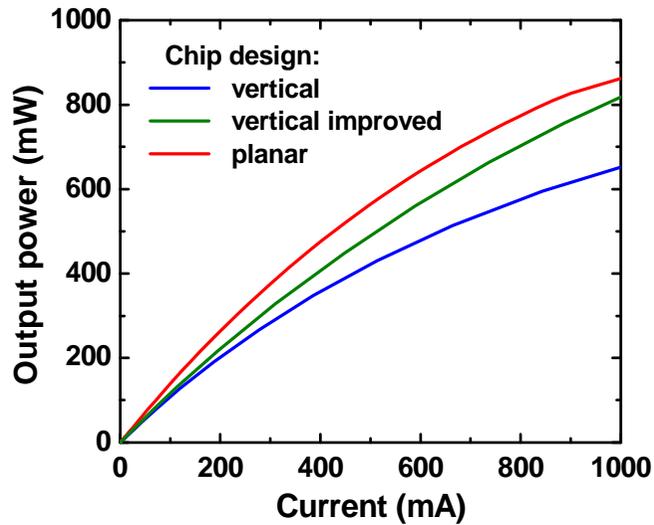
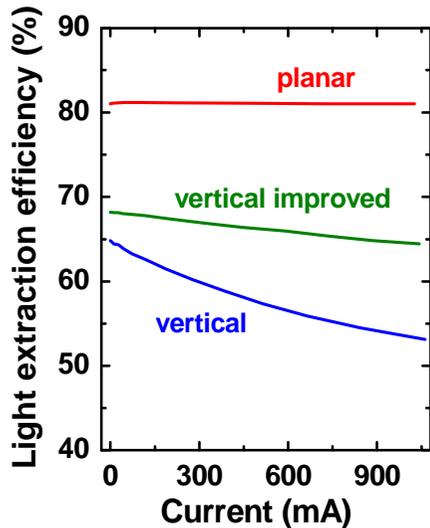
both approaches are found to work well



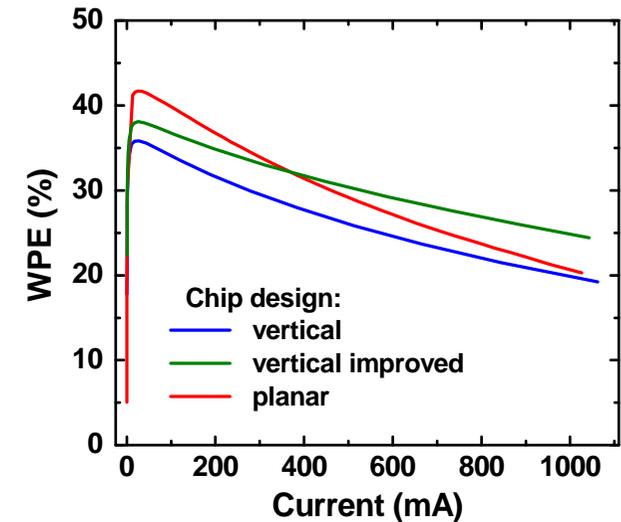
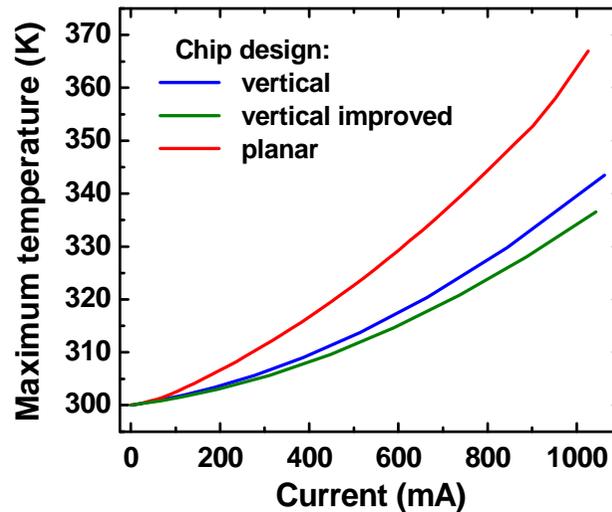
they are combined in the further consideration

reduction of the current density contrast in the active region

# Comparison of characteristics of vertical and planar LEDs



planar LED provides a higher optical power but a stronger droop of both EQE and WPE compared to improved vertical LED



# Assessment of general performance of vertical and planar LEDs

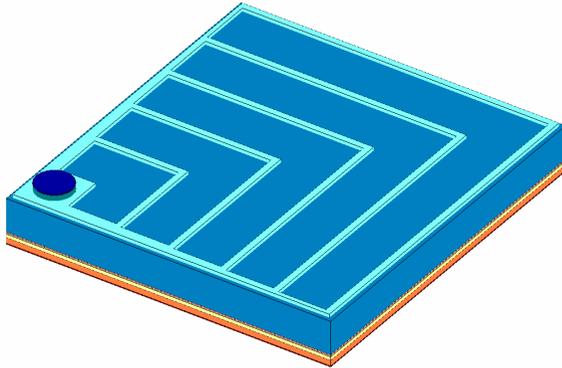


better parameters are marked by yellow color

	Vertical die	Planar die
Operation voltage @ 0.7 A (V)	3.5	4.0
Differential resistance @ 0.7 A ( $\Omega$ )	0.12	0.70
Light extraction efficiency (%)	70 $\rightarrow$ 57 @ I = 1.0 A	81 @ all currents
Optical power @ 0.7 A (mW)	530 (640 for improved)	710
External quantum efficiency (%)		
– peak	44 (47 for improved)	51
– @ 1.0 A	25 (32 for improved)	31
Wall-plug efficiency (%)		
– peak	36 (38 for improved)	42
– @ 1.0 A	20 (25 for improved)	20.5
Local active region overheating @ 0.7 A (K)	22 (19 for improved)	36
Current density non-uniformity $J_{\max}/J_{\text{av}}$ @ 0.7 A	5.3 (4.4 for improved)	10.3
Capability of scaling-up	average	good

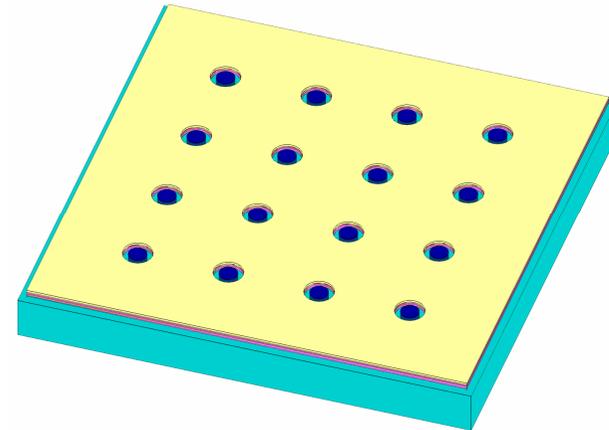
degradation-related characteristics ?

## Possible directions of further improvement of the LED performance



- ✚ using two-pad configuration
- ✚ using ITO + highly reflective n-electrodes
- ✚ optimization of current-blocking (insulating) film
- ✚ optimization of n-electrode geometry

➡ optimization of chip design



- ✚ using LED structure with reduced IQE droop, e.g. DHS
- ✚ optimization of n-electrode geometry (?)
- ✚ improvement of heat-sink (?)

➡ optimization of LED structure